

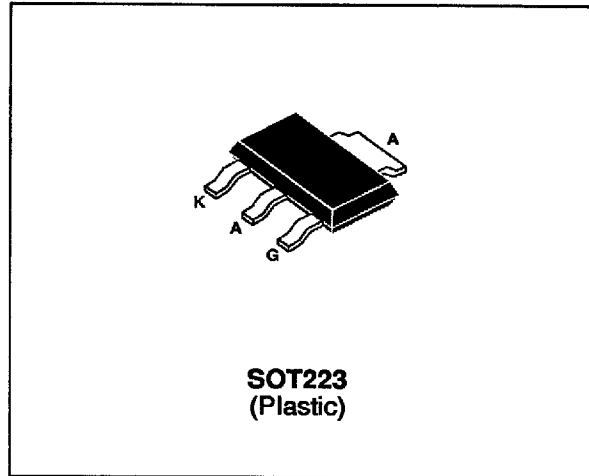
**SENSITIVE GATE SCR**

**FEATURES**

- $I_{T(RMS)} = 0.8A$
- $V_{DRM} = 500V$  to  $800V$
- Low  $I_{GT} \leq 20 \mu A$  max to  $< 200 \mu A$

**DESCRIPTION**

The P0201xN series of SCRs uses a high performance planar PNP technology. These parts are intended for general purpose high volume applications using surface mount technology.



**ABSOLUTE RATINGS (limiting values)**

Symbol	Parameter		Value	Unit
$I_{T(RMS)}$ *	RMS on-state current (180° conduction angle)	$T_a = 80^\circ C$	0.8	A
$I_{T(AV)}$ *	Mean on-state current (180° conduction angle)	$T_a = 80^\circ C$	0.5	A
$I_{TSM}$	Non repetitive surge peak on-state current ( $T_j$ initial = $25^\circ C$ )	$t_p = 8.3$ ms	8	A
		$t_p = 10$ ms	7	
$I^2t$	$I^2t$ Value for fusing	$t_p = 10$ ms	0.24	$A^2s$
$di/dt$	Critical rate of rise of on-state current $I_G = 10$ mA $di_G/dt = 0.1$ A/ $\mu s$ .		30	A/ $\mu s$
$T_{stg}$ $T_j$	Storage and operating junction temperature range		- 40, + 150 - 40, + 125	$^\circ C$
$T_l$	Maximum lead temperature for soldering during 10s		260	$^\circ C$

\* : With  $5cm^2$  copper ( $e=35\mu m$ ) surface under tab.

Symbol	Parameter	Voltage				Unit
		E	M	S	N	
$V_{DRM}$ $V_{RRM}$	Repetitive peak off-state voltage $T_j = 125^\circ C$ $R_{GK} = 1K\Omega$	500	600	700	800	V

# P0201xN

## THERMAL RESISTANCES

Symbol	Parameter	Value	Unit
Rth(j-a)	Junction to ambient *	60	°C/W
Rth(j-t)	Junction to tab for DC	25	°C/W

\* : With 5cm<sup>2</sup> copper (e=35µm) surface under tab.

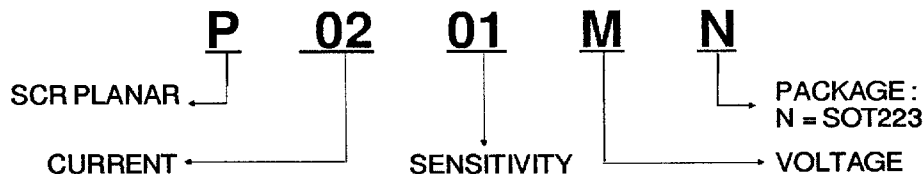
## GATE CHARACTERISTICS (maximum values)

$P_G (AV) = 0.1 W$   $P_{GM} = 2 W$  ( $t_p = 20 \mu s$ )  $I_{GM} = 1 A$  ( $t_p = 20 \mu s$ )

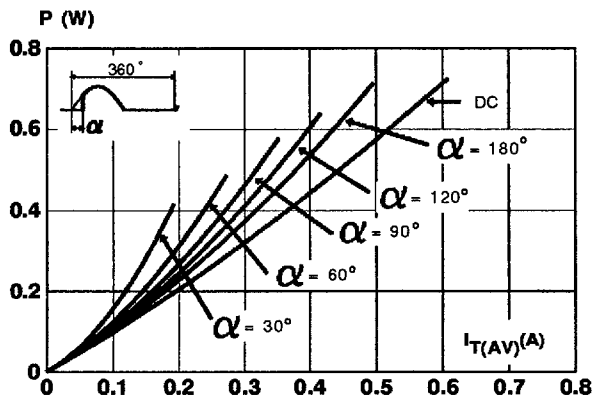
## ELECTRICAL CHARACTERISTICS

Symbol	Test Conditions			Sensitivity		Unit
				01	02	
I <sub>GT</sub>	V <sub>D</sub> =12V (DC) R <sub>L</sub> =140Ω	T <sub>j</sub> = 25°C	MIN	1	-	µA
			MAX	20	200	
V <sub>GT</sub>	V <sub>D</sub> =12V (DC) R <sub>L</sub> =140Ω	T <sub>j</sub> = 25°C	MAX	0.8		V
V <sub>GD</sub>	V <sub>D</sub> =V <sub>DRM</sub> R <sub>L</sub> =3.3kΩ R <sub>GK</sub> = 1 KΩ	T <sub>j</sub> = 125°C	MIN	0.1		V
V <sub>RGM</sub>	I <sub>RG</sub> = 10µA	T <sub>j</sub> = 25°C	TYP	24		V
t <sub>gd</sub>	V <sub>D</sub> =V <sub>DRM</sub> I <sub>TM</sub> = 3 x I <sub>T(AV)</sub> dI <sub>G</sub> /dt = 0.1A/µs I <sub>G</sub> = 10mA	T <sub>j</sub> = 25°C	TYP	0.5		µs
I <sub>H</sub>	I <sub>T</sub> = 50mA R <sub>GK</sub> = 1 KΩ	T <sub>j</sub> = 25°C	MAX	5		mA
I <sub>L</sub>	I <sub>G</sub> =1mA R <sub>GK</sub> = 1 KΩ	T <sub>j</sub> = 25°C	MAX	6		mA
V <sub>TM</sub>	I <sub>TM</sub> = 1.6A t <sub>p</sub> = 380µs	T <sub>j</sub> = 25°C	MAX	1.75		V
I <sub>DRM</sub> I <sub>RRM</sub>	V <sub>D</sub> = V <sub>DRM</sub> R <sub>GK</sub> = 1 KΩ V <sub>R</sub> = V <sub>RRM</sub>	T <sub>j</sub> = 25°C	MAX	10		µA
		T <sub>j</sub> = 125°C	MAX	100		
dV/dt	V <sub>D</sub> =67%V <sub>DRM</sub> R <sub>GK</sub> = 1 KΩ	T <sub>j</sub> = 125°C	TYP	100		V/µs
t <sub>q</sub>	I <sub>TM</sub> = 3 x I <sub>T(AV)</sub> V <sub>R</sub> =35V dI/dt=10A/µs t <sub>p</sub> =100µs dV/dt=2V/µs V <sub>D</sub> = 67%V <sub>DRM</sub> R <sub>GK</sub> = 1 KΩ	T <sub>j</sub> = 125°C	MAX	200		µs

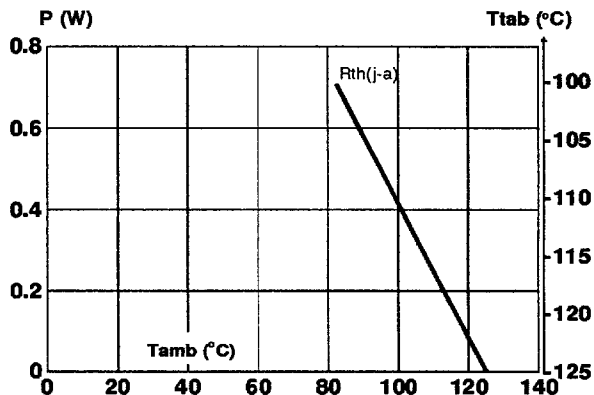
## ORDERING INFORMATION



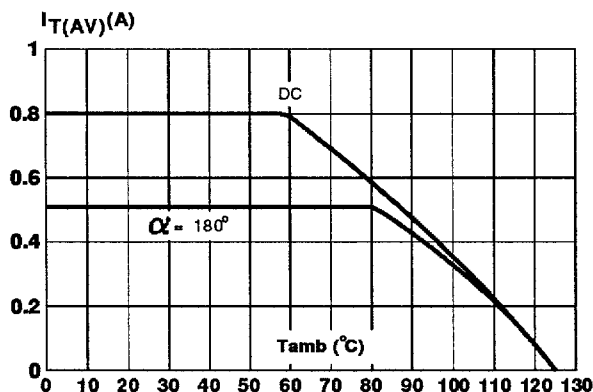
**Fig.1 :** Maximum average power dissipation versus average on-state current.



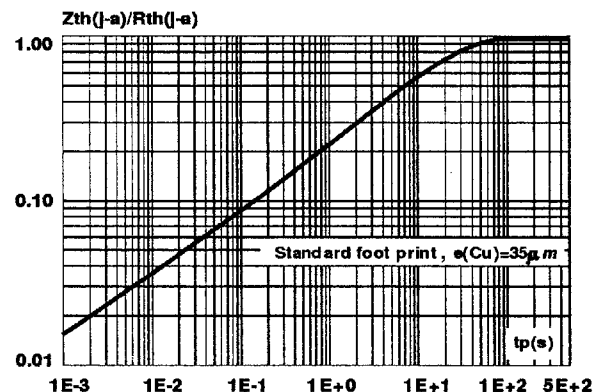
**Fig.2 :** Correlation between maximum average power dissipation and maximum allowable temperature ( $T_{amb}$  and  $T_{tab}$ ).



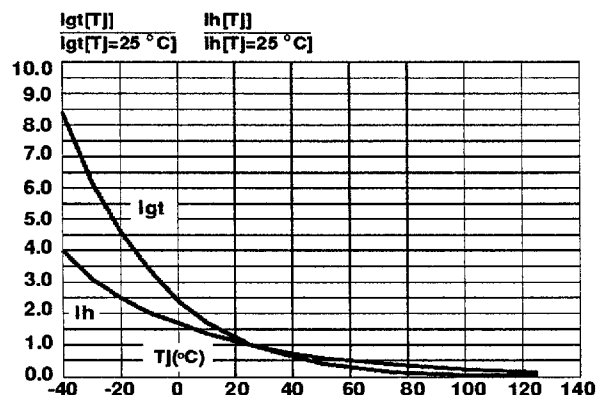
**Fig.3 :** Average on-state current versus tab temperature.



**Fig.4 :** Relative variation of thermal impedance junction to ambient versus pulse duration.



**Fig.5 :** Relative variation of gate trigger current and holding current versus junction temperature.



**Fig.6 :** Non repetitive surge peak on-state current versus number of cycles.

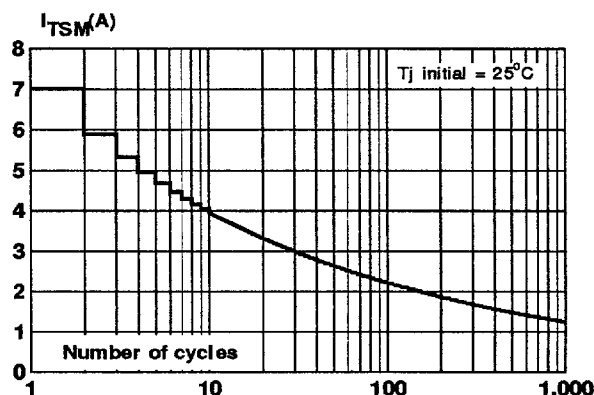


Fig.7 : Non repetitive surge peak on-state current for a sinusoidal pulse with width :  $t_p \leq 10\text{ms}$ , and corresponding value of  $I^2t$ .

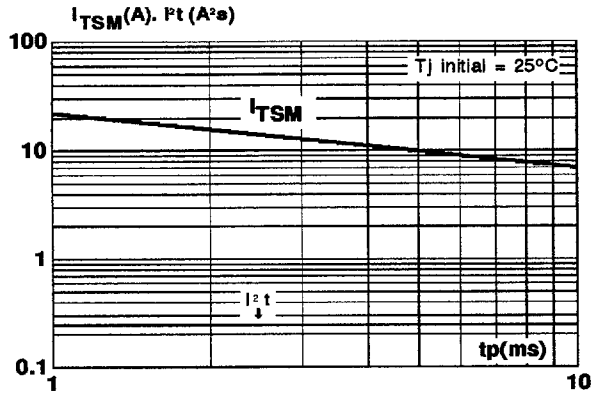


Fig.8 : On-state characteristics (maximum values).

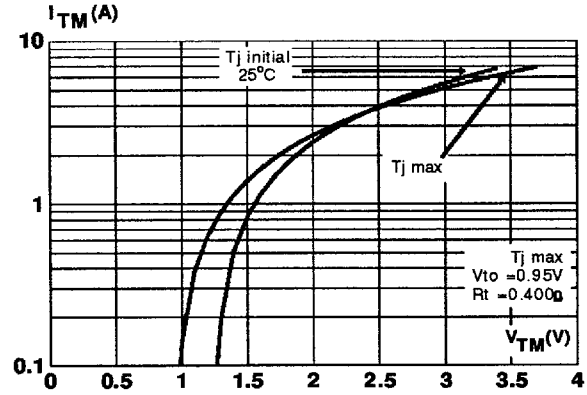
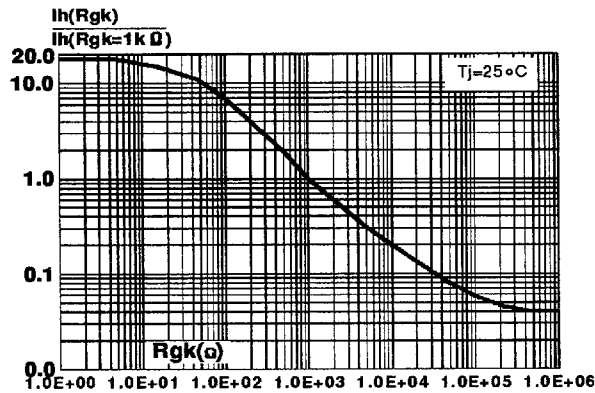
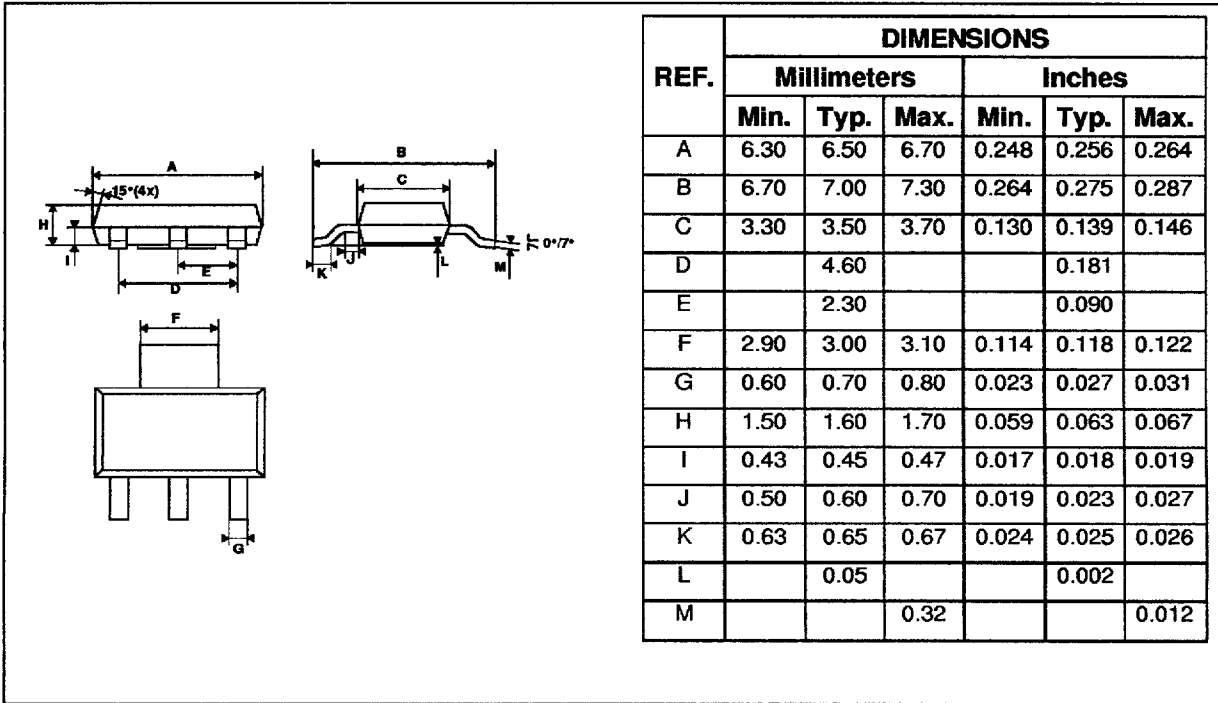


Fig.9 : Relative variation of holding current versus gate-cathode resistance (typical values).

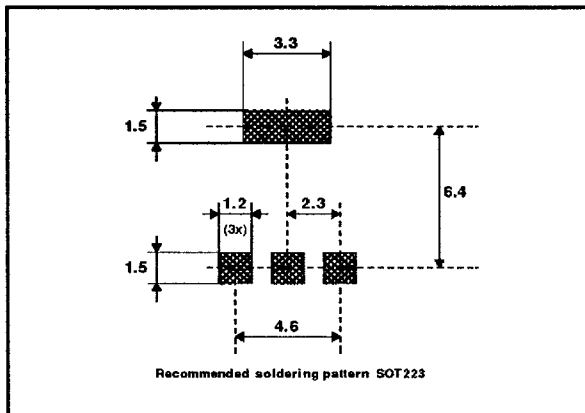


**PACKAGE MECHANICAL DATA**  
SOT223 (Plastic)



Weight : 0.11 g

**FOOT PRINT**



**MARKING**

Type	Marking
P0201EN	P1E
P0201MN	P1M
P0201SN	P1S
P0201NN	P1N
P0202EN	P2E
P0202MN	P2M
P0202SN	P2S
P0202NN	P2N

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